Speckle Measurement System

Powerful Tool for your Development

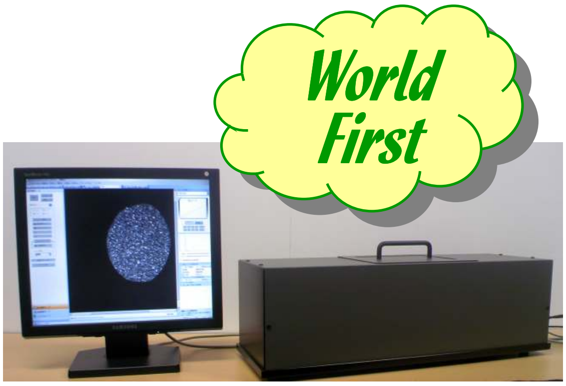
Best Standards for RGB Laser-Display

N.A. Selectability

Good Repeatability

High Contrast Measurement

Based on van Cittert-Zernike Theory



Developed by Dr. Shigeo Kubota
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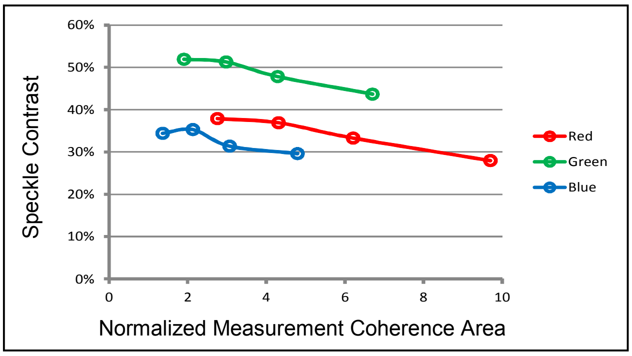
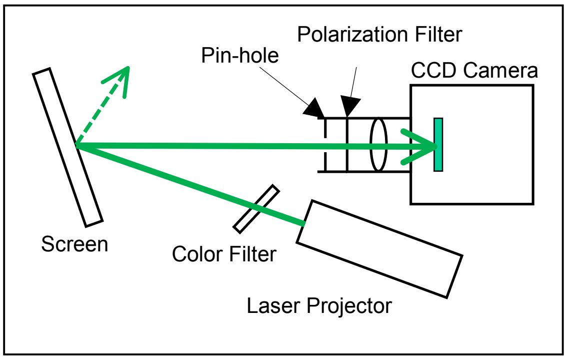


Example Data



Schematic of Optical System

Tentative Specification	
Projector Luminous Flux	> 10 lm
Measurement Screen Size	1” Diameter
Pin-hole Diameter	0.8 / 1.0 / 1.2 / 1.5 mm
Contrast Definition within 2D Region	$C = \sigma / \overline{I}$
Available for	Front Projector (*Development for Rear Projector)
Measurement Signal	Still Image, RGB primaries

This product is in final stage of development in parallel with commercialization. Please contact us for delivery and price.

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